

20V N-Channel Enhancement Mode MOSFET

Description

The AP40N02DF uses advanced trench technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 2.5V. This device is suitable for use as a Battery protection or in other Switching application.

General Features

$V_{DS} = 20V$ $I_D = 40A$

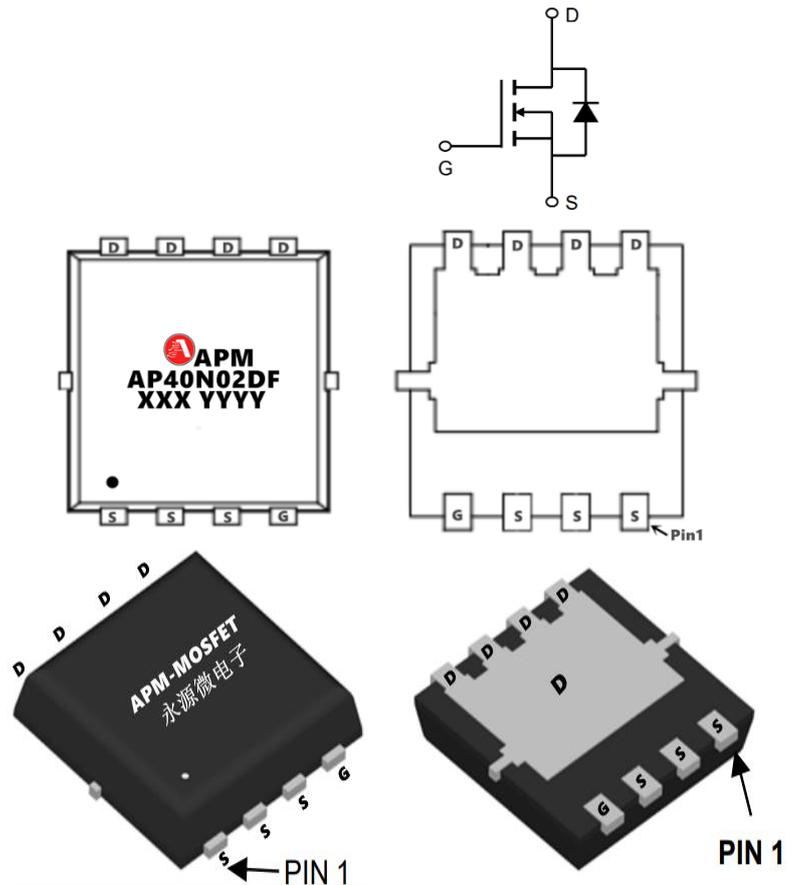
$R_{DS(ON)} < 9m\Omega$ @ $V_{GS}=4.5V$ (Type: 7.0m Ω)

Application

3.3V MCU Drive

Load switch

Uninterruptible power supply



Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
AP40N02DF	PDFN3X3-8L	AP40N02DF XXX YYYY	3000

Absolute Maximum Ratings ($T_C=25^\circ C$ unless otherwise noted)

Symbol	Parameter	Max.	Units
VDSS	Drain-Source Voltage	20	V
VGSS	Gate-Source Voltage	± 12	V
$I_{D@TA=25^\circ C}$	Continuous Drain Current, $V_{GS} @ 4.5V$	40	A
$I_{D@TA=70^\circ C}$	Continuous Drain Current, $V_{GS} @ 4.5V$	25	A
IDM	Pulsed Drain Current <small>note1</small>	110	A
IAS	Avalanche Current	38	A
EAS	Single Pulsed Avalanche Energy <small>note2</small>	130	mJ
$PD@TA=25^\circ C$	Power Dissipation	37	W
T_J, T_{STG}	Operating and Storage Temperature Range	-55 to +175	$^\circ C$
$R_{\theta JA}$	Thermal Resistance Junction-Ambient ¹	85	$^\circ C/W$
$R_{\theta JC}$	Thermal Resistance, Junction to Case	4.8	$^\circ C/W$

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Electrical Characteristics (T_J=25°C, unless otherwise noted)

Symbol	Parameter	Condition	Min	Typ	Max	Unit
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V I _D =250μA	20	22	-	V
IDSS	Zero Gate Voltage Drain Current	V _{DS} =20V, V _{GS} =0V	-	-	1	μA
IGSS	Gate-Body Leakage Current	V _{GS} =±12V, V _{DS} =0V	-	-	±100	nA
VGS(th)	Gate Threshold Voltage	V _{DS} =V _{GS} , I _D =250μA	0.5	0.65	1.2	V
RDS(ON)	Drain-Source On-State Resistance	V _{GS} =4.5V, I _D =6A	-	7.0	9.0	mΩ
RDS(ON)	Drain-Source On-State Resistance	V _{GS} =2.5V, I _D =5A	-	9.3	12	mΩ
gFS	Forward Transconductance	V _{DS} =5V, I _D =20A	10	-	-	S
C _{iss}	Input Capacitance	V _{DS} =10V, V _{GS} =0V, F=1.0MHz		625		PF
C _{oss}	Output Capacitance			162		PF
C _{rss}	Reverse Transfer Capacitance			105		PF
td(on)	Turn-on Delay Time	V _{GS} =10V, V _{DS} =10V RL=0.5Ω, RGEN=3Ω	-	4.5	-	nS
t _r	Turn-on Rise Time		-	9.2	-	nS
td(off)	Turn-Off Delay Time		-	18.7	-	nS
t _f	Turn-Off Fall Time		-	3.3	-	nS
Q _g	Total Gate Charge	V _{GS} =10V, V _{DS} =10V, I _D =20A		15		nC
Q _{gs}	Gate-Source Charge			1.8		nC
Q _{gd}	Gate-Drain Charge			2.8		nC
VSD	Diode Forward Voltage ^(Note 3)	V _{GS} =0V, I _S =25A	-	-	1.2	V
I _S	Diode Forward Current ^(Note 2)		-	-	25	A
t _{rr}	Reverse Recovery Time	T _J = 25°C, I _F = 20A di/dt = 100A/μs	-	18	-	nS
Q _{rr}	Reverse Recovery Charge		-	9.5	-	nC
ton	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by LS+LD)				

Note :

- 1、The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper.
- 2、The data tested by pulsed , pulse width ≤ 300us , duty cycle ≤ 2%
- 3、The power dissipation is limited by 150°C junction temperature
- 4、The data is theoretically the same as ID and IDM , in real applications , should be limited by total power dissipation.

Typical Characteristics

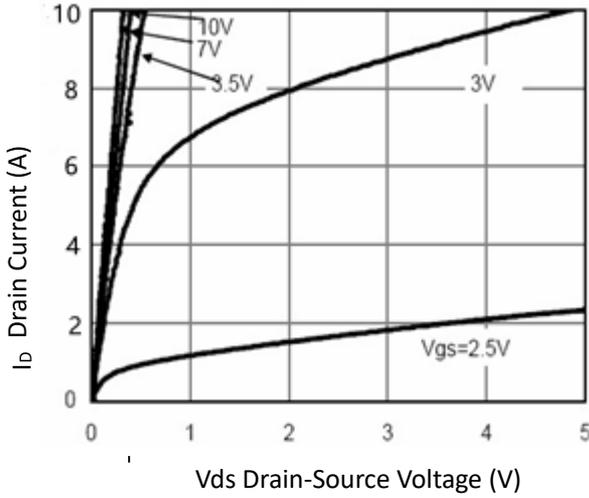


Figure 1 Output Characteristics

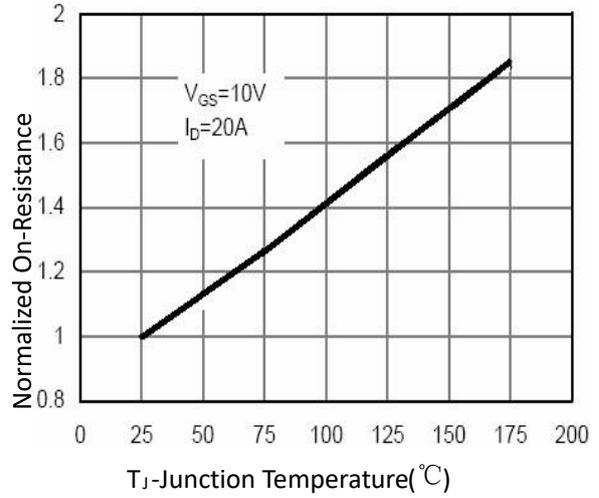


Figure 4 Rds(on)-Junction Temperature

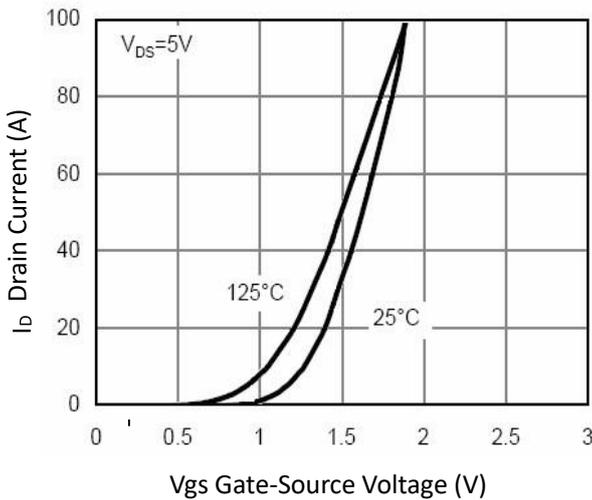


Figure 2 Transfer Characteristics

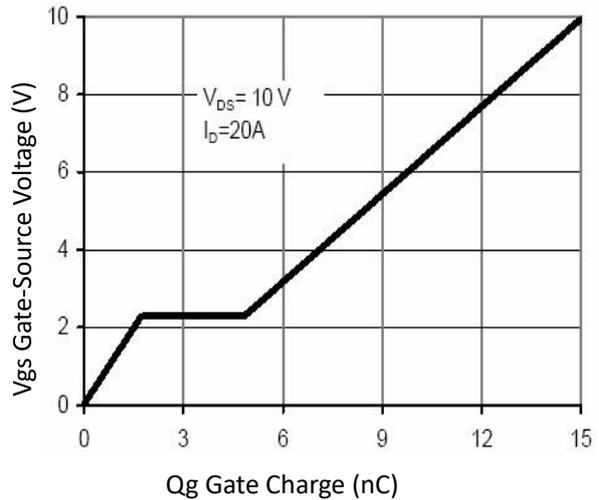


Figure 5 Gate Charge

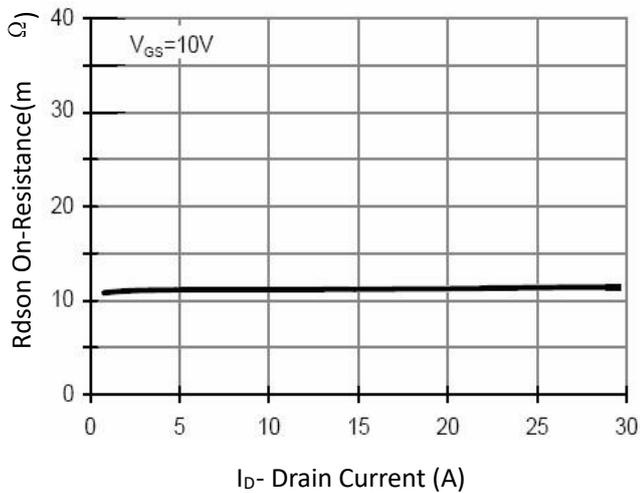


Figure 3 Rds(on)- Drain Current

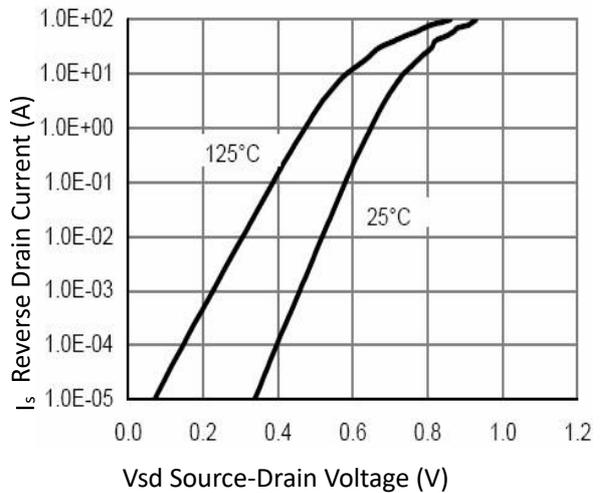


Figure 6 Source- Drain Diode Forward

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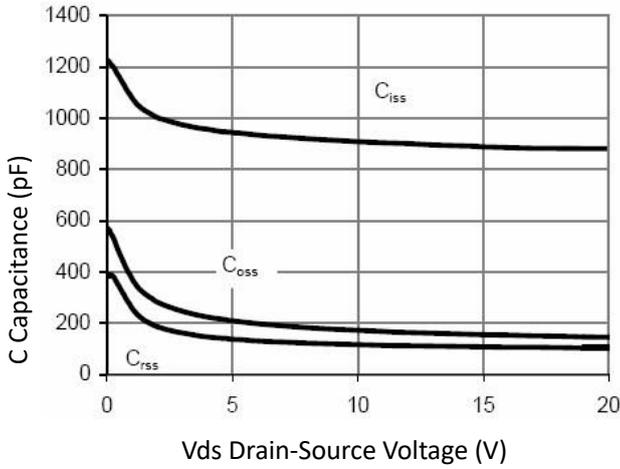


Figure 7 Capacitance vs Vds

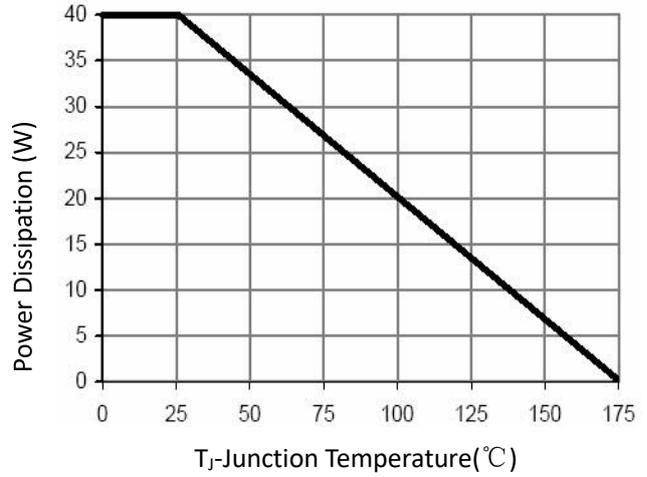


Figure 9 Power De-rating

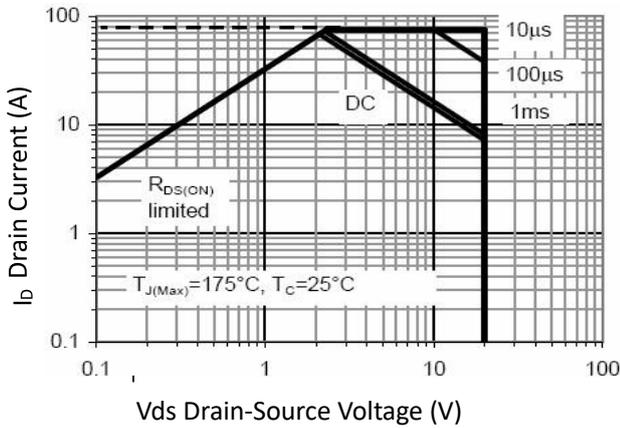


Figure 8 Safe Operation Area

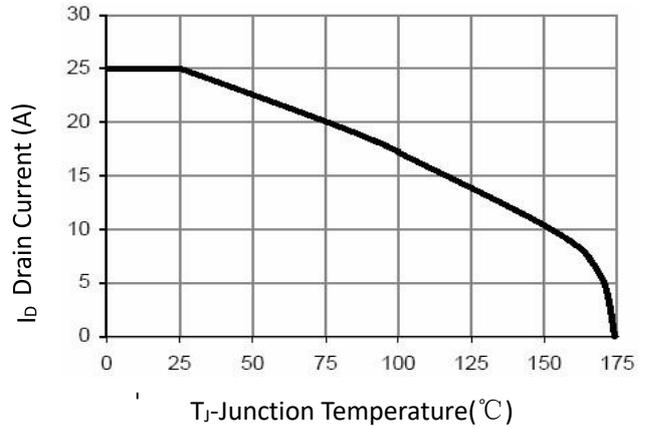


Figure 10 Current De-rating

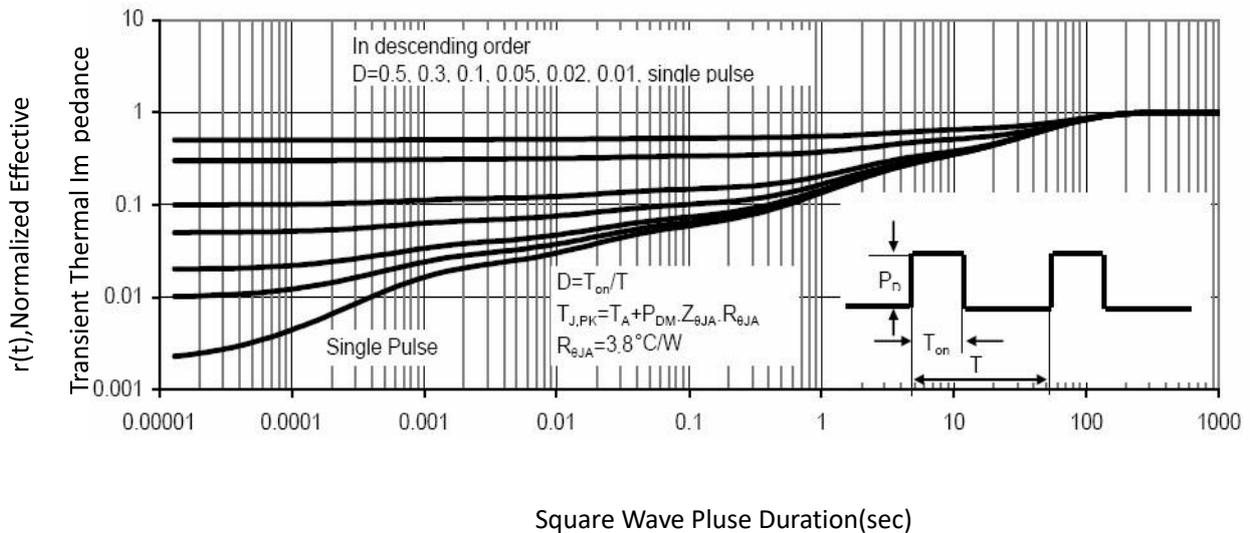
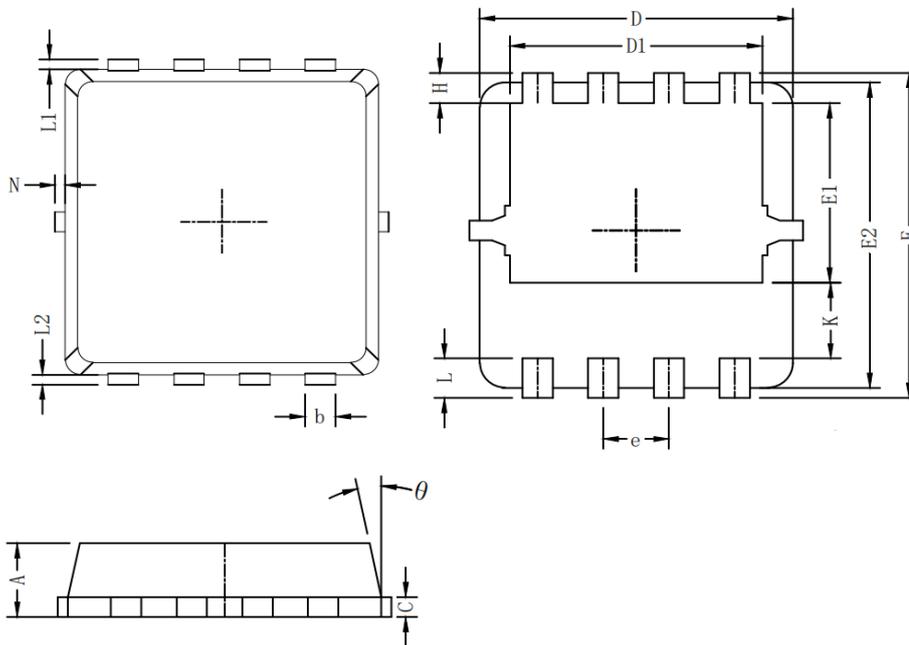


Figure 11 Normalized Maximum Transient Thermal Impedance

Package Mechanical Data-PDFN3X3-8L



Symbol	Dim in mm		
	Min	Typ	Max
A	0.6	0.75	0.9
b	0.2	0.3	0.4
C	0.15	0.2	0.25
D	3	3.1	3.2
D1	2.3	2.45	2.6
E	3.15	3.3	3.45
E1	1.43	1.73	1.93
E2	2.9	3.05	3.2
e	0.65BSC		
H	0.2	0.35	0.5
K	0.57	0.77	0.87
L	0.3	0.4	0.5
L1/L2	0.1REF		
θ	8°	10°	13°
N	0		0.15

20V N-Channel Enhancement Mode MOSFET**Attention**

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Edition	Date	Change
REV1.0	2023/9/31	Initial release

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